

<b>Notice of References Cited</b>	Application/Control No. 10/824,981	Applicant(s)/Patent Under Reexamination BENOIT ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,475,983	11-2002	Eid et al.	514/2
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	WO 92/18626	10-1992	FR	Eid et al	----
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Uze et al. Cell. 1990, 60:225-234
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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